Press Release

Date: 12.04.11

Enclosure:

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New TopSens Surface Sensors from Polytec

Polytec broadens its product portfolio for surface measurement with the instruction of TMS TopSens and TMS TopLine point sensors. Chromatic confocal imaging and confocal spectral interferometry enables the rapid characterization of surfaces for determining of micro/nanotopography, optical surface roughness and thickness measurement of transparent samples. The measuring heads contain no moving parts and are therefore robust and maintenance-free. Applications in the electronics and microelectronics, semiconductor, automotive and micromechanical and optical industry sectors can now be served by these new sensors.

The TopSens sensors are fully compliant with new ISO 25178 regulations and are able to measure roughness values down to a few nanometers. They acquire roughness profiles much faster than a classical tactile probe, without any risk of marking the surface.

The innovative Confocal Chromatic Imaging principle allows measurement of the thickness of transparent materials, with extremely high accuracy.

Further, these new optical sensors allow systematic control on production lines thanks to their very high measuring rates and advanced interfacing with the production line or custom inspection machinery.

Interfaced with 3D scanning devices, these optical sensors give access to full 2-D and 3-D measurements of complex objects or assemblies, with sub-micron accuracy.

Publication free of charge

For questions
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More info: www.topmap.info

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